FORM PTO 1449 (modified)				DOCKET NO. 62.002955.1		APPLICATION NO.  To be assign d			
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			APPL	APPLICANTS ·					
LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				NAOTO ABE, ET AL.					
Submitted to the PTO: July 30, 2003				g DATE y 30, 2003		2674			
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<sup>•</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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